Search Notes		
		(8) 88) 880 880 1881

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/692,800	MIYAKE ET AL.	
Examiner	Art Unit	
Benjamin P. Geib	2181	

	SEARCHED			
Class	Subclass	Date	Examiner	
717	129	2/8/2006	BPG	
712	244	2/9/2006	BPG	
	<u></u>			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
		1 10 10	
			

SEARCH (INCLUDING SEAR		')
	DATE	EXMR
East Search	2/8/2006	BPG
IEEE Xplore Search	2/8/2006	BPG
ACM Search	2/8/2006	BPG
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